

<b>Notice of References Cited</b>	Application/Control No. 10/670,772	Applicant(s)/Patent Under Reexamination CHOI, YOUNG-HUN	
	Examiner Daniel I Walsh	Art Unit 2876	Page 1 of 4

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0129776	07-2004	Choi, Young-Hun	235/380
	B	US-2004/0104805	06-2004	Sakamoto et al.	340/005.74
	C	US-2003/0128822	07-2003	Leivo et al.	379/93.02
	D	US-5,956,557	09-1999	Kato et al.	399/401
	E	US-2004/0060983	04-2004	Davis et al.	235/386
	F	US-2003/0055686	03-2003	Satoh et al.	705/3
	G	US-2001/0035455	11-2001	Davis et al.	235/375
	H	US-2003/0151600	08-2003	Takeuchi et al.	345/204
	I	US-2003/0014372	01-2003	Wheeler et al.	705/71
	J	US-2002/0016913	02-2002	Wheeler et al.	713/170
	K	US-2002/0013769	01-2002	Murase, Shigeo	705/40
	L	US-2004/0139044	07-2004	Rehwald, Jorg	707/001
	M	US-2004/0138921	07-2004	Broussard et al.	705/002

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
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#### NON-PATENT DOCUMENTS

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	U	
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<b>Notice of References Cited</b>	Application/Control No. 10/670,772		Applicant(s)/Patent Under Reexamination CHOI, YOUNG-HUN	
	Examiner Daniel I Walsh		Art Unit 2876	Page 2 of 4

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0117308	06-2004	Bouknight, Wendell J. JR.	705/044
	B	US-2004/0005051	01-2004	Wheeler et al.	380/28
	C	US-2003/0200445	10-2003	Park, Kyun-hoe	713/185
	D	US-2003/0135727	07-2003	Challener et al.	713/2
	E	US-2003/0088780	05-2003	Kuo et al.	713/185
	F	US-2003/0074575	04-2003	Hoberock et al.	713/200
	G	US-2002/0178366	11-2002	Ofir, Amiran	713/182
	H	US-2002/0029348	03-2002	Du et al.	713/193
	I	US-2001/0045451	11-2001	Tan et al.	235/375
	J	US-2001/0002487	05-2001	Grawrock et al.	713/193
	K	US-6,575,373	06-2003	Nakano, Hiroo	235/492
	L	US-5,877,483	03-1999	Bilich et al.	235/382
	M	US-5,410,713	04-1995	White et al.	713/330

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
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	S					
	T					

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<b>Notice of References Cited</b>	Application/Control No. 10/670,772	Applicant(s)/Patent Under Reexamination CHOI, YOUNG-HUN	
	Examiner Daniel I Walsh	Art Unit 2876	Page 3 of 4

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,901,068	02-1990	Benton et al.	340/5.65
	B	US-6,012,632	01-2000	Bouthillier et al.	235/375
	C	US-2004/0134992	07-2004	Guez et al.	235/492
	D	US-2003/0126483	07-2003	Huang et al.	713/310
	E	US-6,128,744	10-2000	Wang, Cheng-Chih	713/300
	F	US-2003/0191960	10-2003	Hung-yi, Yang	713/200
	G	US-6,173,282	01-2001	McCaughan et al.	707/9
	H	US-6,738,901	05-2004	Boyles et al.	713/159
	I	US-2003/0051040	03-2003	Tanikawa et al.	709/229
	J	US-5,969,630	10-1999	Leih et al.	340/7.1
	K	US-2002/0091586	07-2002	Wakai et al.	705/26
	L	US-2001/0034623	10-2001	Chung, Kevin Kwong-Tai	705/5
	M	US-5,534,975	07-1996	Stefik et al.	399/1

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
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	R					
	S					
	T					

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<b>Notice of References Cited</b>	Application/Control No. 10/670,772	Applicant(s)/Patent Under Reexamination CHOI, YOUNG-HUN	
	Examiner Daniel I Walsh	Art Unit 2876	Page 4 of 4

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,067,621	05-2000	Yu et al.	713/172
	B	US-5,327,497	07-1994	Mooney et al.	235/382
	C	US-2003/0121972	07-2003	Lee et al.	235/380
	D	US-2002/0020752	02-2002	KING, REGINALD ALFRED	235/492
	E	US-4,684,791	08-1987	Bito, Hiroyasu	235/380
	F	US-5,286,954	02-1994	Sato et al.	235/379
	G	US-6,705,520	03-2004	Pitroda et al.	235/382.5
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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